

**Search Notes****Application/Control No.**

10/774,690

**Examiner**

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**Applicant(s)/Patent under Reexamination**

TANAKA ET AL.

**Art Unit**

2821

**SEARCHED**

Class	Subclass	Date	Examiner
315	111.21-111.71	1/19/2006	LA
422	168-183	1/19/2006	LA
422	186.04	1/19/2006	LA
422	186.18	1/19/2006	LA
423	210	1/19/2006	LA
423	235	1/19/2006	LA
423	245.1	1/19/2006	LA

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Updated EAST prior art text search (see "Examiner Search Notes")	1/19/2006	LA
EAST interference text search (see "Examiner Search Notes")	1/19/2006	LA

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
315	111.21-111.71	1/19/06	za
422	168-183	1/19/06	za
422	186.04, 186.18	1/19/06	za
423	210, 235, 245.1	1/19/06	za